

Reveo-0130USAAON00
09/765,880

REMARKS

Applicants wish to thank the Examiner for the attention accorded to the instant application.

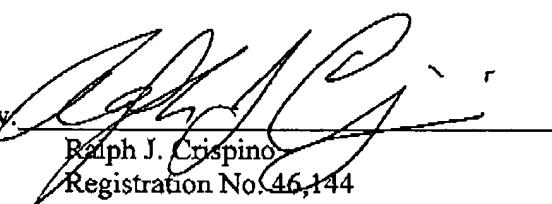
Claims 1-14 and 32 remain pending in the application. Claims 1, 2, 3 and 32 were amended in an amendment submitted June 6, 2005.

It is respectfully submitted that none of the references, alone or in combination, do not teach a system wherein the index of refraction of the liquid crystal array and the index of refraction of the polymer matrix, n_p , are mismatched at least at a first, a second and a third applied electric field strengths, the first, second and third field strengths of increasing magnitude, further wherein a characteristic wavelength reflection varies between the first and third applied field, and a characteristic reflectance intensity varies between first and second applied field and varies between the second and third applied field.

The Examiner has maintained his rejection of claims 1-4, 7-13 and 32 as being anticipated by Sutherland et al. U.S. Patent No. 5,942,157. However, unlike the claims herein, Sutherland does not teach that the characteristic wavelength reflection and that the characteristic reflectance intensity vary across at least three applied electric fields.

Applicants respectfully submit that claims 1-14 and 32 are in condition for allowance. Early notice to that effect is earnestly solicited.

Respectfully submitted,

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